

## Applications Include:

- Visual Inspection
- Defect Review
- OCR
- Sorting
- Second Optical Inspection
- Image Storage & Retrieval
- Overlay Measurement
- Laser Marking
- GEM/SECS II
- Host Communication – LAN
- UV Microscope Interface

## SITEview™ is a True user-oriented optical inspection and metrology package:

- Single screen operations eliminate screen clutter
- Multi-level password protection
- User customizable screen appearance, buttons & functions
- Recipe's created on or offline are available to all systems via Host (LAN) connection
- One software version for all systems & configurations for 50mm – 300mm wafers

## OCR & Sorting

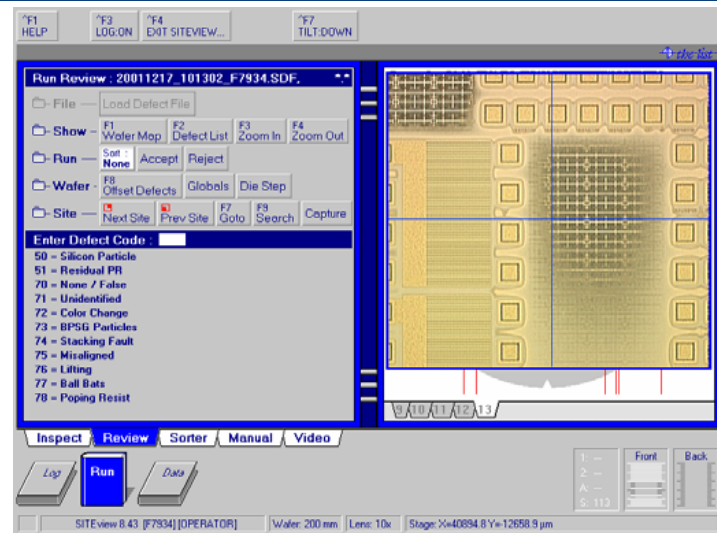
- Front or Backside scribe
- Inventory file stores wafer history by ID AND Slot, Lot log in / out time & date, duration at each inspection point, wafer or defect classification
- Enables full sorting functions – Move, Compress, Randomize, Find, Align, Verify and Split Lot.

## Defect Review

- Compatible with all defect file types
- Cassette BCR operation automatically loads defect file
- View Defect Map, Defect List, Defect Live or Stored Image
- Auto-Defect Search routine, Defect Offset, Binning, user definable defect code list and one click defect image storage

## Second Optical Inspection

- Download probe test file
- Siteview creates good/bad Die wafer map and generates “S” scan at selected Die for review. Can enter defect codes
- OCR # and defect data is appended to original file and sent to Host



## Overlay Metrology

- Incorporate “Box in Box” or “Frame in Frame” Overlay measurements within a visual inspection recipe
- Automated measurements with pattern recognition used for global and local alignment

## LAN Interface

Recipe's & Images are stored on a Host computer. If connection is lost, system will work from local drive and automatically switch to Host when connection is restored